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| Form 1449 (Modified) | Atty Docket No. KLA1P117X1F/P1151/7 | Application No.: 10/785,430 |
| Information Disclosure Statement By Applicant | Applicant: Mieher, et al. | |
| (Use Several Sheets if Necessary) | Filing Date February 23, 2004 | Group 2877 |

U.S. Patent Documents

| Examiner Initial | No. | Patent No. | Date | Patentee | Class | Sub-class | Filing Date |
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Foreign Patent or Published Foreign Patent Application

| Examiner Initial | No. | Document No. | Publication Date | Country or Patent Office | Class | Sub-class | Translation | |
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| Examiner /Gordon Stock Jr/ | | Date Considered 09/26/2006 |

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